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First Named Inventor	: William D. Jensen et al.	Group Art Unit: 2816 Examiner:
Appln. No.	: 09/970,074	
Filed	: October 2, 2001	
Title	: METHOD AND APPARATUS FOR TRIMMING INTEGRATED CIRCUITS	
Docket No.	: V44.12-0149	

INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner for Patents
Washington, D.C. 20231

I CERTIFY THAT THIS PAPER IS BEING SENT BY U.S. MAIL, FIRST CLASS, TO THE ASSISTANT COMMISSIONER FOR PATENTS, WASHINGTON, D.C. 20231, THIS 19 DAY OF

December, 2001.

PATENT ATTORNEY

Sir:

The enclosed PTO Form-1449 lists patents and publications submitted pursuant to 37 C.F.R. 1.97. Copies of the patents or publications are enclosed as necessary.

TIME OF FILING

The Information Disclosure Statement is being filed with the application or within three months of the filing date of a national application (other than a continued prosecution application under 37 C.F.R. 1.53(d)) or date of entry into the national stage of an international application or, to the best of the undersigned's knowledge, before the mailing date of a first Office action on the merits or a first office action after the filing of a request for continued examination under 37 C.F.R. 1.114, whichever event occurs last. In accordance with 37 C.F.R. 1.97(b), no certification or fee is required.

Respectfully submitted,

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FORM PTO-1449

Atty. Docket No.:
V44.12-0149Application No.:
09/970,074LIST OF PATENTS AND PUBLICATIONS FOR
APPLICANT'S INFORMATION
DISCLOSURE STATEMENTFirst Named Inventor:
William D. JensenFiling Date:
October 2, 2001Group Art:
2816

U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
AA	Re. 32,625	3/15/1988	Schwarz et al.	374	57	8/18/1986
AB	3,974,443	8/10/1976	Thomas	324	64	1/2/1975
AC	4,024,561	5/17/1977	Ghatalia	H01L 29	78	4/1/1976
AD	4,319,396	3/16/1982	Law et al.	29	571	12/28/1979
AE	4,801,869	1/31/1989	Sprogis	324	73	4/27/1987
AF	4,918,377	4/17/1990	Buehler et al.	324	691	12/5/1988
AG	6,006,169	12/21/1999	Sandhu et al.	702	132	12/31/1997
AH	6,028,756	2/22/2000	Freyman et al.	361	104	3/11/1998
AI	6,108,804	8/22/2000	Derner	714	721	9/11/1997
AJ	6,175,261 BI	1/16/2001	Sundaraman et al.	327	525	1/7/1999
AK	6,211,745 BI	4/3/2001	Mucke et al.	331	117R	5/3/1999

FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Class	Sub Class	Translation Yes No
AL						
AM						
AN						

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AO	V. Ryan, Acceleration of Stress-Migration Failure in Aluminum Interconnect, June 17, 1992, Pages 1-13.
AP	V. Ryan, Enhanced Stress-Migration Reliability for ULSI Interconnect: An Insight into the Perils of Screening Al Depositions Based on Grain Size, 1995
AQ	F.G. Yost, Stress-Voiding of Narrow Conductor Lines, 1990, pages 40-44

EXAMINER:

DATE CONSIDERED:

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.